

April 2015

# H11AA1M, H11AA4M 6-Pin DIP AC Input Phototransistor Optocouplers

### **Features**

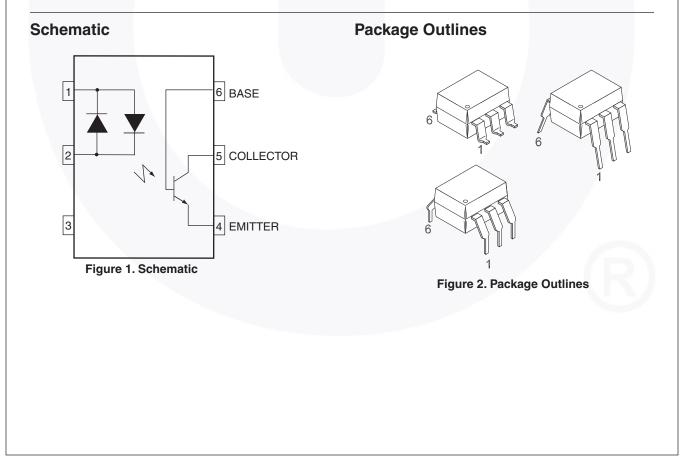
- Bi-polar Emitter Input
- Built-in Reverse Polarity Input Protection
- Safety and Regulatory Approvals:
  - UL1577, 4,170 VAC<sub>RMS</sub> for 1 Minute
  - DIN-EN/IEC60747-5-5, 850 V Peak Working Insulation Voltage

### Applications

- AC Line Monitor
- Unknown Polarity DC Sensor
- Telephone Line Interface

### Description

The H11AA1M and H11AA4M devices consist of two gallium-arsenide infrared emitting diodes connected in inverse parallel driving a single silicon phototransistor output.



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### Safety and Insulation Ratings

As per DIN EN/IEC 60747-5-5, this optocoupler is suitable for "safe electrical insulation" only within the safety limit data. Compliance with the safety ratings shall be ensured by means of protective circuits.

Parameter	Characteristics	
Installation Classifications per DIN VDE	< 150 V <sub>RMS</sub>	I–IV
0110/1.89 Table 1, For Rated Mains Voltage	< 300 V <sub>RMS</sub>	I–IV
Climatic Classification		55/100/21
Pollution Degree (DIN VDE 0110/1.89)		2
Comparative Tracking Index		175

Symbol	Parameter	Value	Unit
V	Input-to-Output Test Voltage, Method A, $V_{IORM} \times 1.6 = V_{PR}$ , Type and Sample Test with t <sub>m</sub> = 10 s, Partial Discharge < 5 pC	1360	V <sub>peak</sub>
V <sub>PR</sub>	Input-to-Output Test Voltage, Method B, $V_{IORM} \times 1.875 = V_{PR}$ , 100% Production Test with $t_m = 1 \text{ s}$ , Partial Discharge < 5 pC	1594	V <sub>peak</sub>
VIORM	Maximum Working Insulation Voltage	850	V <sub>peak</sub>
V <sub>IOTM</sub>	Highest Allowable Over-Voltage	6000	V <sub>peak</sub>
	External Creepage	≥ 7	mm
	External Clearance	≥ 7	mm
	External Clearance (for Option TV, 0.4" Lead Spacing)	≥ 10	mm
DTI	Distance Through Insulation (Insulation Thickness)	≥ 0.5	mm
Τ <sub>S</sub>	Case Temperature <sup>(1)</sup>	175	°C
I <sub>S,INPUT</sub>	Input Current <sup>(1)</sup>	350	mA
P <sub>S,OUTPUT</sub>	Output Power <sup>(1)</sup>	800	mW
R <sub>IO</sub>	Insulation Resistance at T <sub>S</sub> , $V_{IO}$ = 500 V <sup>(1)</sup>	> 10 <sup>9</sup>	Ω

Note:

1. Safety limit values - maximum values allowed in the event of a failure.

## **Absolute Maximum Ratings**

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Value	Unit
TOTAL DEVIC	E		
T <sub>STG</sub>	Storage Temperature	-40 to +125 °C	
T <sub>OPR</sub>	Operating Temperature	-40 to +100	°C
Т <sub>Ј</sub>	Junction Temperature	-40 to +125	°C
T <sub>SOL</sub>	Lead Solder Temperature	260 for 10 seconds	°C
	Total Device Power Dissipation @ 25°C	n @ 25°C 270 m	
P <sub>D</sub>	Derate Linearly From 25°C	2.94	mW/°C
EMITTER			
١ <sub>F</sub>	Continuous Forward Current	60	mA
l <sub>F</sub> (pk)	Forward Current – Peak (1 µs pulse, 300 pps)	±1.0	
LED Power Dissipation @ 25°C		120	mW
PD	Derate Linearly From 25°C	From 25°C 1.41	
DETECTOR			
۱ <sub>C</sub>	Continuous Collector Current	50	mA
P <sub>D</sub>	Detector Power Dissipation @ 25°C	150	mW
	Derate linearity from 25°C	1.76	mW/°C

## **Electrical Characteristics**

 $T_A=25^\circ C$  Unless otherwise specified.

#### Individual Component Characteristics

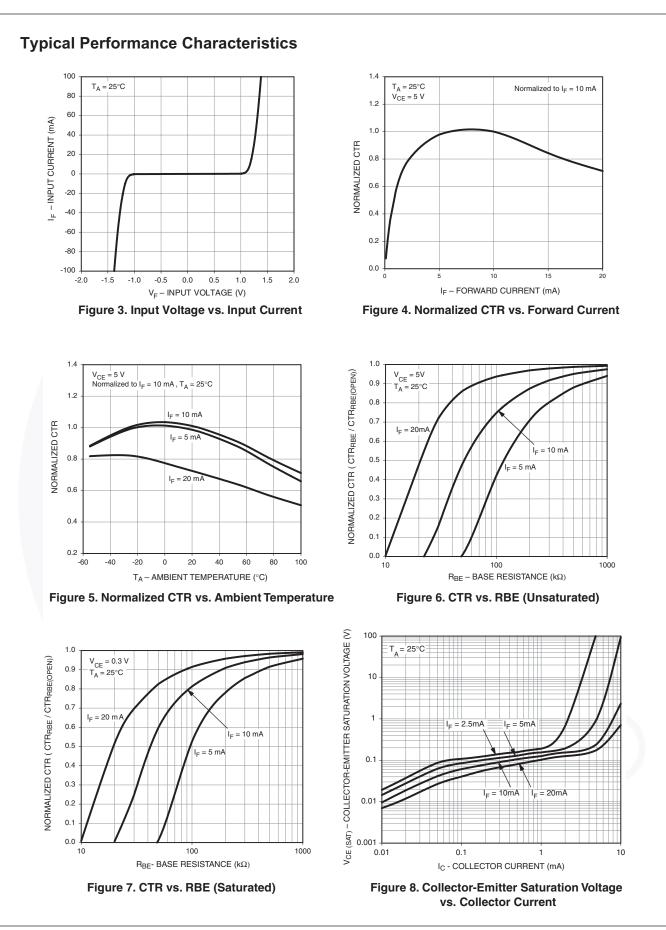
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
EMITTER			1	1	1	
V <sub>F</sub>	Input Forward Voltage	$I_F = \pm 10 \text{ mA}$		1.17	1.50	V
CJ	Capacitance	V <sub>F</sub> = 0 V, f = 1.0 MHz		80		pF
DETECTO	R					
BV <sub>CEO</sub>	Breakdown Voltage, Collector-to-Emitter	I <sub>C</sub> = 1.0 mA, I <sub>F</sub> = 0	30	100		V
BV <sub>CBO</sub>	Breakdown Voltage, Collector-to-Base	$I_{C} = 100 \ \mu A, I_{F} = 0$	70	120		V
BV <sub>EBO</sub>	Breakdown Voltage, Emitter-to-Base	I <sub>E</sub> = 100 μA, I <sub>F</sub> = 0	5	10		V
BV <sub>ECO</sub>	Breakdown Voltage, Emitter-to-Collector	I <sub>E</sub> = 100 μA, I <sub>F</sub> = 0	7	10		V
I <sub>CEO</sub>	Leakage Current, Collector-to-Emitter	$V_{CE} = 10 \text{ V}, \text{ I}_{F} = 0$		1	50	nA
C <sub>CE</sub>	Capacitance Collector to Emitter	$V_{CE} = 0, f = 1 MHz$		10		pF
C <sub>CB</sub>	Collector to Base	$V_{CB} = 0, f = 1 MHz$		80		pF
C <sub>EB</sub>	Emitter to Base	$V_{EB} = 0, f = 1 MHz$		15		pF

### **Transfer Characteristics**

Symbol	Characteristics	Test Conditions	Device	Min.	Тур.	Max.	Unit
CTR <sub>CE</sub>	Current Transfer Ratio,	I <sub>F</sub> = ±10 mA, V <sub>CE</sub> = 10 V	H11AA1M	20			%
OTTCE	Collector-to-Emitter	$r_{\rm F} = \pm 10$ mA, $v_{\rm CE} = 10$ v	H11AA4M	100			%
	Current Transfer Ratio, Symmetry	$I_F = \pm 10 \text{ mA}, V_{CE} = 10 \text{ V}$ (Figure 13)	All	0.33		3.00	
V <sub>CE(SAT)</sub>	Saturation Voltage, Collector-to-Emitter	$I_{\rm F} = \pm 10$ mA, $I_{\rm CE} = 0.5$ mA	All			0.40	V

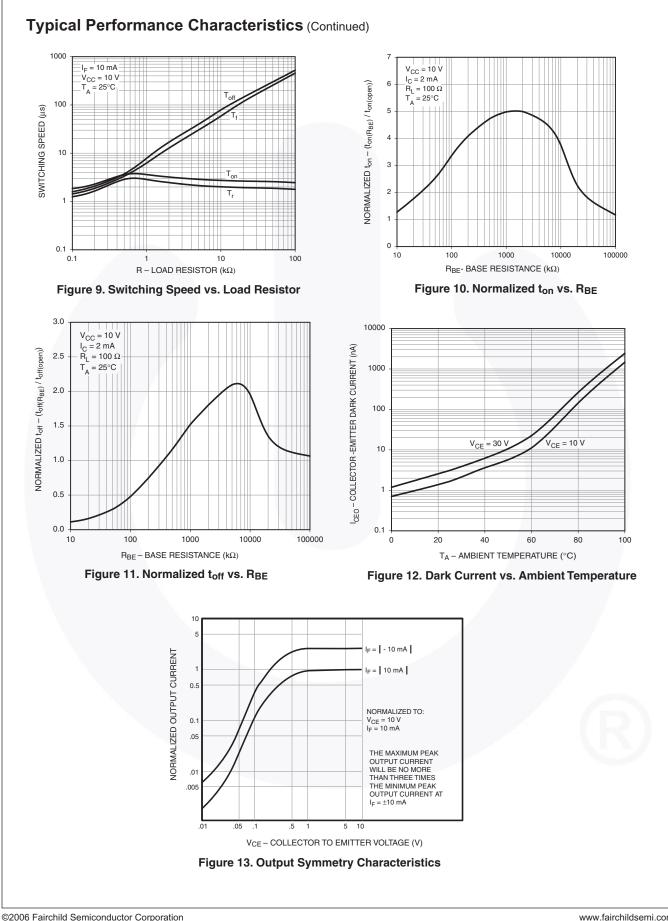
#### **Isolation Characteristics**

Symbol	Characteristic	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>ISO</sub>	Input-Output Isolation Voltage	t = 1 Minute	4170			VAC <sub>RMS</sub>
C <sub>ISO</sub>	Isolation Capacitance	V <sub>I-O</sub> = 0 V, f = 1 MHz		0.7		pF
R <sub>ISO</sub>	Isolation Resistance	V <sub>I-O</sub> = ±500 VDC, T <sub>A</sub> = 25°C	10 <sup>11</sup>			Ω

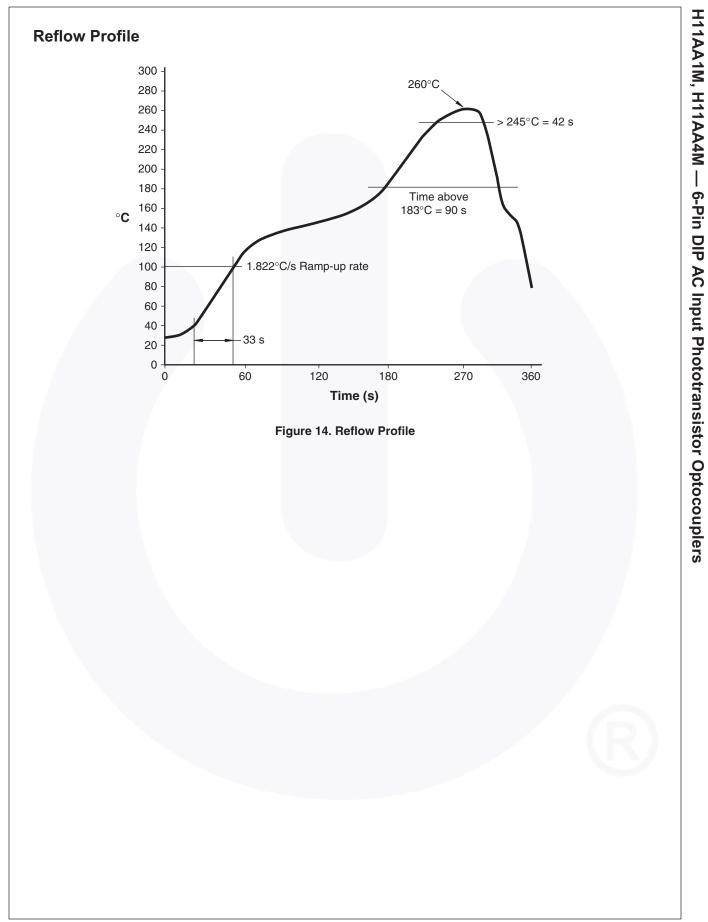


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H11AA1M, H11AA4M — 6-Pin DIP AC Input Phototransistor Optocouplers



H11AA1M, H11AA4M Rev. 1.3



## **Ordering Information**

Part Number	Package	Packing Method
H11AA1M	DIP 6-Pin	Tube (50 Units)
H11AA1SM	SMT 6-Pin (Lead Bend)	Tube (50 Units)
H11AA1SR2M	SMT 6-Pin (Lead Bend)	Tape and Reel (1000 Units)
H11AA1VM	DIP 6-Pin, DIN EN/IEC60747-5-5 Option	Tube (50 Units)
H11AA1SVM	SMT 6-Pin (Lead Bend), DIN EN/IEC60747-5-5 Option	Tube (50 Units)
H11AA1SR2VM	SMT 6-Pin (Lead Bend), DIN EN/IEC60747-5-5 Option	Tape and Reel (1000 Units)
H11AA1TVM	DIP 6-Pin, 0.4" Lead Spacing, DIN EN/IEC60747-5-5 Option	Tube (50 Units)

#### Note:

2. The product orderable part number system listed in this table also applies to the H11AA4M device.

### **Marking Information**

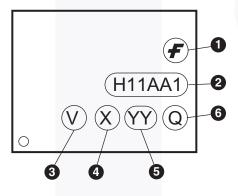
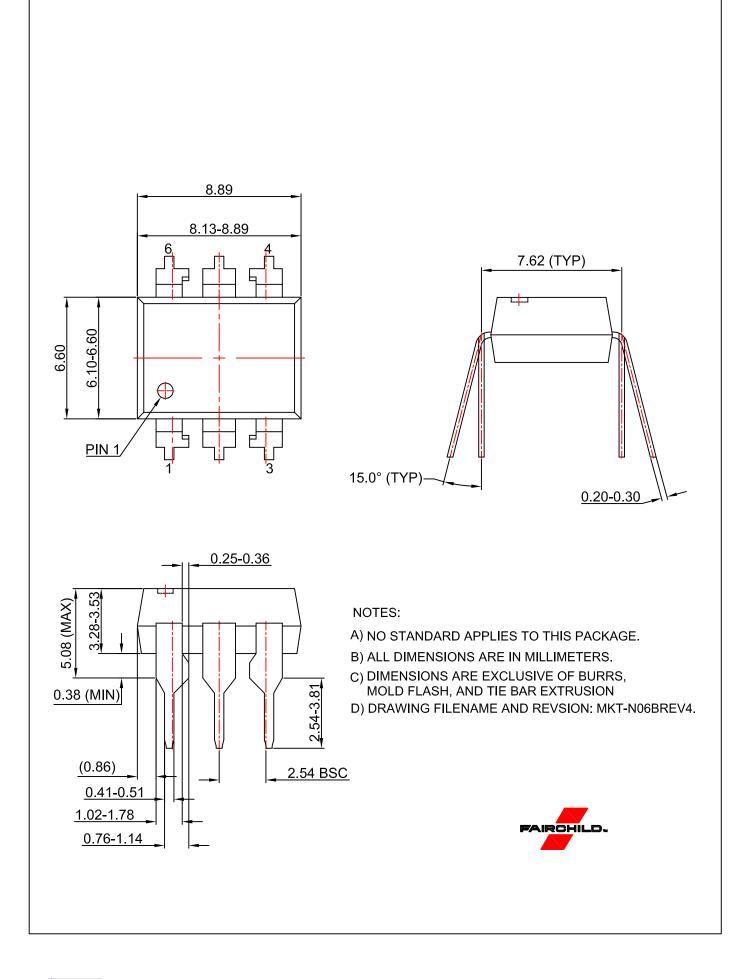
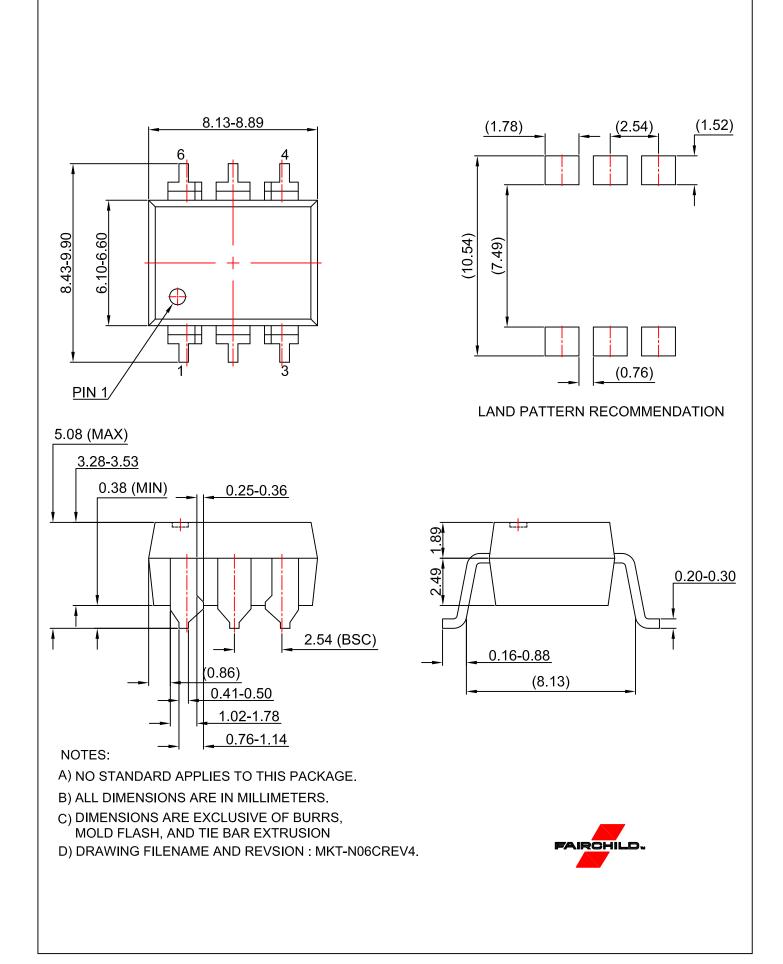


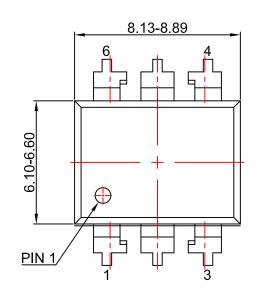
Figure 15. Top Mark

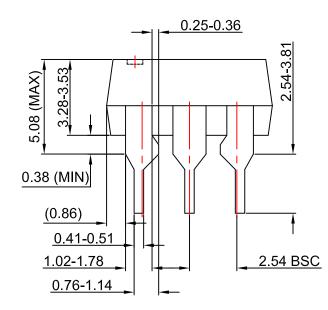
#### Table 1. Top Mark Definitions

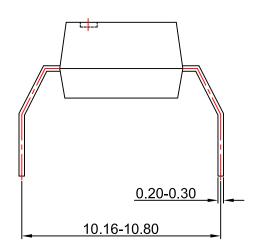
1	Fairchild Logo
2	Device Number
3	DIN EN/IEC60747-5-5 Option (only appears on component ordered with this option)
4	One-Digit Year Code, e.g., "5"
5	Digit Work Week, Ranging from "01" to "53"
6	Assembly Package Code











#### NOTES:

- A) NO STANDARD APPLIES TO THIS PACKAGE.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSION
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